



PCN: A06-016-480051-0A

Product Change Notice

Issue Date: 21 July 2006

Change Type:

Test related changes: Frequency points change for AMMC-5040.

Parts Affected:

All options of AMMC-5040.

Description and Extent of Change:

100% on-wafer RF test will be tested at 5 frequency points as stated below:

Existing test points: 21, 24, 27, 29, 37, 40 and 45 GHz

New test points: 23, 27, 29, 37 and 40 GHz

Reasons for Change:

Improve manufacturability by removing non-critical test frequencies.

Effect of Change on Fit, Form, Function, Quality, or Reliability:

There are no changes to product form, fit, function, quality or reliability. The new device test frequencies will be reflected on the new datasheet.

Effective Date of Change:

Product shipments using this change will begin on or around Oct 22, 2006, but initiation of the change may be spread over approximately six months depending on customer demand and inventory levels.

These changes have been reviewed and approved by Avago Technologies engineers and managers per Avago Technologies procedure: Change Control and Customer Notification, A-5962-6052-80.

Please contact your Avago field sales engineer or Contact Center (<http://www.Avagotech.com/support/contact/>) for any questions or support requirements.